



<p style="text-align: center;">Searched</p> 	<p>Application/Control No.</p> <p>08932543</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>KAWAKURA ET AL.</p>
	<p>Examiner</p> <p>Tran, Hai</p>	<p>Art Unit</p> <p>2623</p>


Class	SubClass	Date	Examiner
725	25,27,29,100,104,122	8/7/2006	HVT
726	26-33	8/7/06	HVT

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Search Notes 	Application/Control No. 08932543	Applicant(s)/Patent Under Reexamination KAWAKURA ET AL.
	Examiner Tran, Hai	Art Unit 2623

Notes	Date	Examiner
UPDATE SEARCH	8/7/06	HVT
Annan Shang (725); Son Huynh (725); Jones Clyder (725)	8/3/06	HVT

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	Examiner Tran, Hai	Art Unit 2623

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See Attached Interference Searched		8/7/06	HVT
U.S. Patent and Trademark Office		Part of Paper No.:	20060807